

Edition 2.1 2013-04

INTERNATIONAL STANDARD





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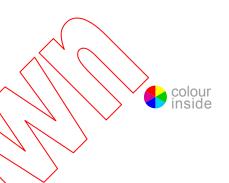
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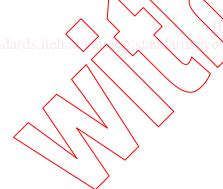
INTERNATIONAL STANDARD

NORME INTERNATIONALE



Static var compensators (SVC) - Testing of thyristor valves

Compensateurs statiques de puissance réactive (SVC) – Essais des valves à thyristors



INTERNATIONAL ELECTROTECHNICAL COMMISSION

COMMISSION ELECTROTECHNIQUE INTERNATIONALE

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

STATIC VAR COMPENSATORS (SVC) – TESTING OF THYRISTOR VALVES

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This consolidated version of IEC 61954 consists of the second edition (2011) [documents 22F/217/CDV and 22F/231A/RVC] and its amendment 1 (2013) [documents 22F/274/CDV and 22F/287A/RVC]. It bears the edition number 2.1.

The technical content is therefore identical to the base edition and its amendment and has been prepared for user convenience. A vertical line in the margin shows where the base publication has been modified by amendment 1. Additions and deletions are displayed in red, with deletions being struck through.

International Standard IEC 61954 has been prepared by subcommittee 22F: Power electronics for electrical transmission and distribution systems, of IEC technical committee 22: Power electronics.

This edition includes the following significant technical changes with respect to the previous edition:

- a) Definitions of terms "thyristor level", "valve section", "valve base electronics" and "redundant thyristor levels" have been changed for clarification.
- b) Conditions of testing thyristor valve sections instead of a complete thyristor valve have been defined.
- c) The requirement has been added that if, following a type test, one thyristor level has become short-circuited, then the failed level shall be restored and this type test repeated.
- d) The time period of increasing the initial test voltage from 50 % to 100 % during type a.c. dielectric tests on TSC, TCR or TSR valves has been set equal to approximately 10 s.
- e) The duration of test voltage $U_{\rm ts2}$ during type a.c.-d.c. dielectric tests between TSC valve terminals and earth as well as the duration of test voltage U_{tvv2} during dielectric tests between TSC valves (for MVU only) has been changed from 30 min to 3 h.
- f) The reference on the number of pulses per minute of the periodic partial discharge recorded during a.c.-d.c. dielectric tests on TSC valves and exceeding the permissible level has been deleted.

This publication has been drafted in accordance with the SOUECNDirectives, Part 2.

The committee has decided that the contents of the base publication and its amendment will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed.
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STATIC VAR COMPENSATORS (SVC) - TESTING OF THYRISTOR VALVES

1 Scope

This International Standard defines type, production and optional tests on thyristor valves used in thyristor controlled reactors (TCR), thyristor switched reactors (TSR) and thyristor switched capacitors (TSC) forming part of static VAR compensators (SVC) for power system applications. The requirements of the standard apply both to single valve units (one phase) and to multiple valve units (several phases).

Clauses 4 to 7 detail the type tests, i.e. tests which are carried out to verify that the valve design meets the requirements specified. Clause 8 covers the production tests, i.e. tests which are carried out to verify proper manufacturing. Clauses 9 and 10 detail optional tests, i.e. tests additional to the type and production tests.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60060 (all parts), High-voltage test techniques

IEC 60060-1, High-voltage test techniques - Part 1. General definitions and test requirements

IEC 60060-2, High-voltage test techniques - Part 2: Measuring systems

IEC 60071 (all parts), Insulation co-ordination

IEC 60071-1:2006, Insulation co-ordination - Part 1: Definitions, principles and rules

IEC 60270, High-voltage test techniques – Partial discharge measurements

IEC 60700-1:2008, Thyristor valves for high-voltage direct current (HVDC) power transmission – Part 1: Electrical testing

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply:

3.1

thyristor level

part of a thyristor valve comprising a thyristor, or thyristors connected in parallel or antiparallel, together with their immediate auxiliaries and reactor, if any

3.2

thyristor (series) string

series connected thyristors forming one direction of a thyristor valve

3.3

valve reactor

reactor incorporated within some valves for limitation of stresses

NOTE For testing purposes it is considered an integral part of the valve.

3.4

valve section

electrical assembly, comprising a number of thyristors and other components, which exhibits pro-rated electrical properties of a complete thyristor valve but only a portion of the full voltage blocking capability of the thyristor valve and which can be used for tests

3.5

thyristor valve

electrically and mechanically combined assembly of thyristor levels, complete with all connections, auxiliary components and mechanical structures, which can be connected in series with each phase of the reactor or capacitor of a SVC

3.6

valve structure

physical structure which insulates the valves to the appropriate level above earth potential and from each other

3.7

valve base electronics

VRF

electronic unit, at earth potential, which is the interface between the control system of the SVC and the thyristor valves

3.8

multiple valve unit

MVU

assembly of several valves in the same physical structure which cannot be separated for test purposes (e.g. three-phase valves)

3.9

redundant thyristor levels

the maximum number of thyristor levels in the thyristor valve that may be short-circuited, externally or internally, during service without affecting the safe operation of the thyristor valve as demonstrated by type tests; and which if and when exceeded, would require either the shutdown of the thyristor valve to replace the failed thyristors, or the acceptance of increased risk of failures

3.10

voltage breakover (VBO) protection

means of protecting the thyristors from excessive voltage by firing them at a predetermined voltage

4 General requirements for type, production and optional tests

4.1 Summary of tests

Table 1 lists the tests given in the following clauses and subclauses.

Table 1 – List of tests

Tes	st	Clause or	Test object	
		TCR/TSR	TSC	
Dielectric tests between v	alve terminals and earth	(type tests)		
AC test		5.1.2	/	Walve
AC-DC test		6.1.2	Valve	
Lightning impulse test	5.1.3	6.1.3	Valve	
Dielectric tests between v	alves (MVU only) (type te	ests)	V / //	
AC test	C test			MVU
AC-DC test			6,2.2	MVU
Lightning impulse test		5.2.3	6.2.3	MVU
Dielectric tests between v	alve terminals (type test	s)		
AC test	iTe	5.3.2		Valve
AC-DC test			6.3.2	Valve
Switching impulse test	https://sta	5.3.3	6.3.3	Valve
Operational tests (type tes	sts)		· ·	
Periodic firing and extinction	test	5.4.1	I I C VV	Valve or valve section
Overcurrent test			6.4.1	Valve or valve section
Minimum a.c. voltage test		5.4.2	6.4.2	Valve or valve section
Temperature rise test		5.4.3	6.4.3	Valve or valve section
Electromagnetic interferen	ce tests (type tests)			
Switching impulse test		7.2.2	7.2.2	Valve
Non-periodic firing test		7.2.3	7.2.3	Valve
Production tests				
Visual inspection		8.2	8.2	
Connection check	>	8.3	8.3	
Voltage dividing/damping ci	rcuit check	8.4	8.4	
Voltage withstand check		8.5	8.5	
Check of auxiliaries		8.6	8.6	
Firing check		8.7	8.7	
Cooling system pressure tes	8.8	8.8		
Partial discharge tests	8.9	8.9		
Optional tests				
Overcurrent test	Overcurrent test			Valve or valve section
Positive voltage transient du	uring recovery test	9.2	10.1	Valve or valve section
Non-periodic firing test		9.3	10.2	Valve

4.2 Objectives of tests

4.2.1 General

The tests described apply to the valve (or valve sections), the valve structure and those parts of the coolant distribution system and firing and monitoring circuits which are contained within the valve structure or connected between the valve structure and earth. Other equipment, such as valve control and protection and valve base electronics may be essential for demonstrating the correct function of the valve during the tests but are not in themselves the subject of the tests.

- 10 -

4.2.2 Dielectric tests

4.2.2.1 **General**

Tests for the following dielectric stresses are specified:

- a.c. voltage;
- combined a.c. and d.c. voltage (TSC only);
- impulse voltages.

In the interest of standardization with other equipment, lightning impulse tests between valve terminals and earth and between phases of an MVU are included. For tests between valve terminals, the only impulse test specified is a switching impulse.

4.2.2.2 Tests on valve structure

Tests are defined for the voltage with stand requirements between a valve (with its terminals short-circuited) and earth, and also between valves for MVU. The tests shall demonstrate that

- sufficient clearances have been provided to prevent flashovers;
- there is no disruptive discharge in the insulation of the valve structure, cooling ducts, light guides and other insulation parts of the pulse transmission and distribution systems;
- partial discharge inception and extinction voltages under a.c. and d.c. conditions are above the maximum steady-state operating voltage appearing on the valve structure.

4.2.2.3 Tests between valve terminals

The purpose of these tests is to verify the design of the valve with respect to its capability to withstand overvoltages between its terminals. The tests shall demonstrate that

- sufficient internal insulation has been provided to enable the valve to withstand specified voltages;
- partial discharge inception and extinction voltages under a.c. and d.c. conditions are above the maximum steady-state operating voltage appearing between valve terminals;
- the protective overvoltage firing system (if provided) works as intended;
- the thyristors have adequate du/dt capability for in-service conditions. (In most cases the specified tests are sufficient; however in some exceptional cases additional tests may be required).

4.2.3 Operational tests

The purpose of these tests is to verify the valve design for combined voltage and current stresses under normal and abnormal repetitive conditions as well as under transient fault conditions. They shall demonstrate that, under specified conditions:

the valve functions properly;

- the turn-on and turn-off voltage and current stresses are within the capabilities of the thyristors and other internal circuits;
- the cooling provided is adequate and no component is overheated;
- the overcurrent withstand capability of the valve is adequate.

4.2.4 Electromagnetic interference tests

The principal objective of these tests is to demonstrate the immunity of the valve to electromagnetic interference from within the valve and from outside the valve. Generally, immunity to electromagnetic interference is demonstrated by monitoring of the valve during other tests.

4.2.5 Production tests

The objective of tests is to verify proper manufacture. The production tests shall demonstrate that

- all materials, components and sub-assemblies used in the valve have been correctly installed;
- the valve equipment functions as intended, and predefined parameters are within prescribed acceptance limits;
- thyristor levels and valve or valve sections have the necessary voltage withstand capability;
- consistency and uniformity in production is achieved.

4.2.6 Optional tests

Optional tests are additional tests which may be performed, subject to agreement between the purchaser and the supplier. The objectives are the same as for the operational tests specified in 4.2.2. The test object is normally one valve or appropriate equivalent number of valve sections.

http: 4.3 an Guidelines for the performance of type and optional tests aa90ab913652/iec-61954-2011

The following principles shall apply:

- type tests shall be performed on at least one valve or on an appropriate number of valve sections, as indicated in Table 1 (see 4.1), to verify that the valve design meets the specified requirements. All type tests shall be performed on the same valve(s) or valve section(s);
- provided that the valve is demonstrably similar to one previously tested, the supplier may submit a certified report of any previous type test, at least equal to the requirements specified in the contract, in lieu of the type test;
- for type tests performed on valve sections, the total number of thyristor levels subjected to such type tests shall be at least equal to the number of thyristor levels in a valve;
- the valve or valve sections used for type tests shall first pass all production tests. On completion of the type test programme, the valve or valve sections shall be checked again for compliance with the production test criteria;
- material for the type tests shall be selected at random;
- the dielectric tests shall be performed in accordance with IEC 60060-1 and IEC 60060-2 where applicable;
- individual tests may be performed in any order.

NOTE Tests involving partial discharge measurement may provide added confidence if performed at the end of the dielectric type test programme.

4.4 Test conditions

4.4.1 General

4.4.1.1 Dielectric test objects

Dielectric tests shall be performed on completely assembled valves, whereas some operational tests may be performed on either complete valves or valve sections. Tests that may be performed on valve sections are identified in 4.1.

The valve shall be assembled with all auxiliary components except for the valve arrester, if used. Unless otherwise specified, the valve electronics shall be energized. The cooling and insulating fluids in particular shall be in a condition that represents service conditions such as conductivity, except for the flow rate and antifreezing media content, which can be reduced. If any object or device external to the structure is necessary for proper representation of the stresses during the test, it shall also be present or simulated in the test. Metallic parts of the valve structure (or other valves in a MVU) which are not part of the test shall be shorted together and connected to earth in a manner appropriate to the test in question.

4.4.1.2 Atmospheric correction

When specified in the relevant clause, atmospheric correction shall be applied to the test voltages in accordance with IEC 60060-1. The reference conditions to which correction shall be made are the following:

– pressure:

If the insulation coordination of the tested part of the thyristor valve is based on standard rated withstand voltages according to IEC 60071-1, correction factors are only applied for altitudes exceeding 1 000 m. Hence if the altitude of the site $a_{\rm s}$ at which the equipment will be installed is less than 1 000 m, then the standard atmospheric air pressure (b_0 = 101,3 kPa) shall be used with no correction for altitude. If $a_{\rm s}$ = 1 000 m, then the standard procedure according to IEC 60060-1 is used except that the reference atmospheric pressure b_0 is replaced by the atmospheric pressure corresponding to an altitude of 1 000 m (b_{1000m}).

If the insulation coordination of the tested part of the thyristor valve is not based on standard rated withstand voltages according to IEC 60071-1, then the standard procedure according to

IEC 60060-1 is used with the reference atmospheric pressure b_0 (b_0 = 101,3 kPa).

– temperature:

design maximum valve hall air temperature (°C).

– humidity:

design minimum valve hall absolute humidity (g/m³).

The values to be used shall be specified by the supplier.

Where non-standard test levels are defined by this standard, a site air density correction factor k_d , defined below shall be applied where stated.

The value of k_d shall be determined from the following expression:

$$k_{\rm d} = \frac{b_1}{b_2} \times \frac{273 + T_2}{273 + T_1} \tag{1}$$

where

 b_1 is the laboratory ambient air pressure, expressed in pascals (Pa);